Data sheet acquired from Harris Semiconductor
SCHS251D

CD54/74AC283, CD54/74ACT283

August 1998 - Revised May 2000

4-Bit Binary Fill Adder With Fast Carry

Features

- **Buffered Inputs**
- **Exceeds 2kV ESD Protection MIL-STD-883, Method 3015**
- **SCR-Latchup-Resistant CMOS Process and Circuit Design**
- **Speed of Bipolar FAST™/AS/S with Significantly Reduced Power Consumption**
- **Balanced Propagation Delays**
- **AC Types Feature 1.5V to 5.5V Operation and Balanced Noise Immunity at 30% of the Supply**
- **±24mA Output Drive Current**
  - **Fanout to 15 FAST™ ICs**
  - **Drives 50Ω Transmission Lines**

Description

The ’AC283 and ’ACT283 4-bit binary adders with fast carry that utilize Advanced CMOS Logic technology. These devices add two 4-bit binary numbers and generate a carry-out bit if the sum exceeds 15.

Because of the symmetry of the add function, this device can be used with either all active-HIGH operands (positive logic) or with all active-LOW operands (negative logic). When using positive logic, the carry-in input must be tied LOW if there is no carry-in.

Ordering Information

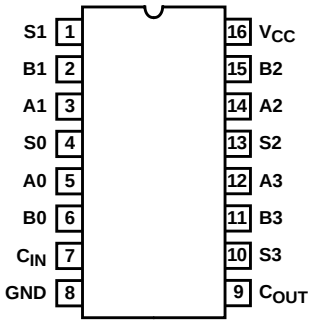
PART NUMBER	TEMP. RANGE (^{o}C)	PACKAGE
CD54AC283F3A	-55 to 125	16 Ld CERDIP
CD74AC283E	0 to 70^{o}C, -40 to 85, -55 to 125	16 Ld PDIP
CD74AC283M	0 to 70^{o}C, -40 to 85, -55 to 125	16 Ld SOIC
CD54ACT283F3A	-55 to 125	16 Ld CERDIP
CD74ACT283E	0 to 70^{o}C, -40 to 85, -55 to 125	16 Ld PDIP
CD74ACT283M	0 to 70^{o}C, -40 to 85, -55 to 125	16 Ld SOIC

NOTES:

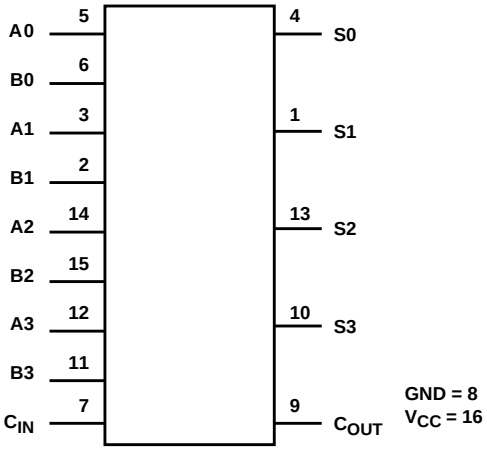
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die for this part number is available which meets all electrical specifications. Please contact your local TI sales office or customer service for ordering information.

Pinout

CD54AC283, CD54ACT283
(CERDIP)
CD74AC283, CD74AC283
(PDIP, SOIC)
TOP VIEW



Functional Diagram



CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

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Absolute Maximum Ratings

DC Supply Voltage, V_{CC} . . . . . -0.5V to 6V
DC Input Diode Current, I_{IK}
For V_I < -0.5V or V_I > V_{CC} + 0.5V . . . . . ±20mA
DC Output Diode Current, I_{OK}
For V_O < -0.5V or V_O > V_{CC} + 0.5V . . . . . ±50mA
DC Output Source or Sink Current per Output Pin, I_O
For V_O > -0.5V or V_O < V_{CC} + 0.5V . . . . . ±50mA
DC V_{CC} or Ground Current, I_{CC} or I_{GND} (Note 3) . . . . . ±100mA

Operating Conditions

Temperature Range, T_A . . . . . -55°C to 125°C
Supply Voltage Range, V_{CC} (Note 4)
AC Types. . . . . 1.5V to 5.5V
ACT Types . . . . . 4.5V to 5.5V
DC Input or Output Voltage, V_I, V_O . . . . . 0V to V_{CC}
Input Rise and Fall Slew Rate, dt/dv
AC Types, 1.5V to 3V . . . . . 50ns (Max)
AC Types, 3.6V to 5.5V. . . . . 20ns (Max)
ACT Types, 4.5V to 5.5V. . . . . 10ns (Max)

Thermal Information

Thermal Impedance (Typical, Note 5) θ_{JA} (°C/W)
PDIP Package . . . . . 67°C/W
SOIC Package . . . . . 73°C/W
Maximum Junction Temperature (Plastic Package) . . . . . 150°C
Maximum Storage Temperature Range . . . . . -65°C to 150°C
Maximum Lead Temperature (Soldering 10s) . . . . . 300°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

3. For up to 4 outputs per device, add ±25mA for each additional output.
4. Unless otherwise specified, all voltages are referenced to ground.
5. The package thermal impedance is calculated in accordance with JESD 51.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
AC TYPES											
High Level Input Voltage	V_{IH}	-	-	1.5	1.2	-	1.2	-	1.2	-	V
				3	2.1	-	2.1	-	2.1	-	V
				5.5	3.85	-	3.85	-	3.85	-	V
Low Level Input Voltage	V_{IL}	-	-	1.5	-	0.3	-	0.3	-	0.3	V
				3	-	0.9	-	0.9	-	0.9	V
				5.5	-	1.65	-	1.65	-	1.65	V
High Level Output Voltage	V_{OH}	V_{IH} or V_{IL}	-0.05	1.5	1.4	-	1.4	-	1.4	-	V
			-0.05	3	2.9	-	2.9	-	2.9	-	V
			-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-4	3	2.58	-	2.48	-	2.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX	
Low Level Output Voltage	V_{OL}	V_{IH} or V_{IL}	0.05	1.5	-	0.1	-	0.1	-	0.1	V
			0.05	3	-	0.1	-	0.1	-	0.1	V
			0.05	4.5	-	0.1	-	0.1	-	0.1	V
			12	3	-	0.36	-	0.44	-	0.5	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	I_I	V_{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	µA
Quiescent Supply Current MSI	I_{CC}	V_{CC} or GND	0	5.5	-	8	-	80	-	160	µA
ACT TYPES											
High Level Input Voltage	V_{IH}	-	-	4.5 to 5.5	2	-	2	-	2	-	V
Low Level Input Voltage	V_{IL}	-	-	4.5 to 5.5	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage	V_{OH}	V_{IH} or V_{IL}	-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V
Low Level Output Voltage	V_{OL}	V_{IH} or V_{IL}	0.05	4.5	-	0.1	-	0.1	-	0.1	V
			24	4.5	-	0.36	-	0.44	-	0.5	V
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V
Input Leakage Current	I_I	V_{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	µA
Quiescent Supply Current MSI	I_{CC}	V_{CC} or GND	0	5.5	-	8	-	80	-	160	µA
Additional Supply Current per Input Pin TTL Inputs High 1 Unit Load	ΔI_{CC}	V_{CC} -2.1	-	4.5 to 5.5	-	2.4	-	2.8	-	3	mA

NOTES:

6. Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
7. Test verifies a minimum 50Ω transmission-line-drive capability at 85°C, 75Ω at 125°C.

ACT Input Load Table

INPUT	UNIT LOAD
A0, B0, A2, B2	1.66
A1, B1	1.9
A3, B3	1.4
C_{IN}	1.1

NOTE: Unit load is ΔI_{CC} limit specified in DC Electrical Specifications Table, e.g., 2.4mA max at 25°C.

Switching Specifications Input t_r, t_f = 3ns, C_L = 50pF (Worst Case)

PARAMETER	SYMBOL	V_{CC} (V)	-40°C TO 85°C			-55°C TO 125°C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
AC TYPES									
Propagation Delay, An or Bn to C_{OUT}, C_{IN} to Sn, C_{IN} to C_{OUT}	t_{PLH}, t_{PHL}	1.5	-	-	199	-	-	219	ns
		3.3 (Note 9)	6.3	-	22.4	6.2	-	24.6	ns
		5 (Note 10)	4.5	-	16	4.4	-	17.6	ns
Propagation Delay, An or Bn to Sn	t_{PLH}, t_{PHL}	1.5	-	-	207	-	-	228	ns
		3.3	6.6	-	23.2	6.4	-	25.5	ns
		5	4.7	-	16.5	4.6	-	18.2	ns
Input Capacitance	C_I	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C_{PD} (Note 11)	-	-	120	-	-	120	-	pF
ACT TYPES									
Propagation Delay, An or Bn to C_{OUT}, C_{IN} to Sn, C_{IN} to C_{OUT}	t_{PLH}, t_{PHL}	5 (Note 10)	4.5	-	16	2.7	-	17.6	ns
Propagation Delay, An or Bn to Sn	t_{PLH}, t_{PHL}	5	4.7	-	16.5	3.3	-	18.2	ns
Input Capacitance	C_I	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C_{PD} (Note 11)	-	-	120	-	-	120	-	pF

NOTES:

8. Limits tested 100%.
9. 3.3V Min is at 3.6V, Max is at 3V.
10. 5V Min is at 5.5V, Max is at 4.5V.
11. C_{PD} is used to determine the dynamic power consumption per function.
    AC: $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$
    ACT: $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.

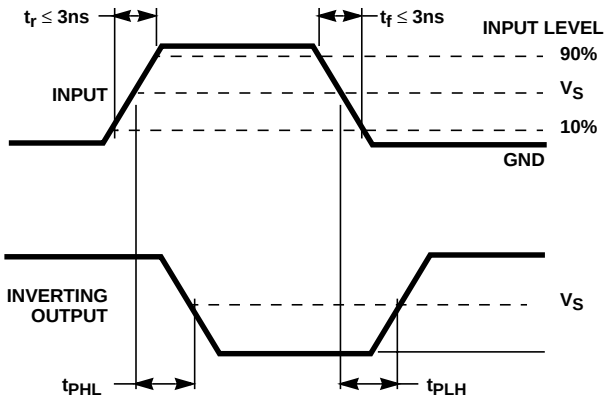
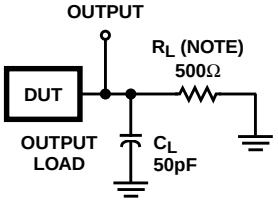


FIGURE 1. PROPAGATION DELAY TIMES



NOTE: For AC Series Only: When V_{CC} = 1.5V, R_L = 1kΩ.

	AC	ACT
Input Level	V_{CC}	3V
Input Switching Voltage, V_S	0.5 V_{CC}	1.5V
Output Switching Voltage, V_S	0.5 V_{CC}	0.5 V_{CC}

FIGURE 2. PROPAGATION DELAY TIMES

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